

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination ZAUDTKE ET AL.	
		Examiner Christopher B. Shin	Art Unit 2182	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,735,663	05-2004	Watts et al.	710/313
	C	US-6,868,375	03-2005	Margulieux, Gordon	703/25
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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